Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/580,451	KOHEN, RAN	
Examiner	Art Unit	
Hae M. Hyeon	2839	

SEARCHED							
Class	Subclass	Date	Examiner				
439	21	4/01	hmh				
439	20						
439	13						
439	537						
439	953						
439	23						
439	348						
439	320						
439	321	1	V				

INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		